

Search Notes

Application/Control No.

10/620,840

Examiner

Shin-Lin Chen

Applicant(s)/Patent under
Reexamination

DUFF, KAREN

Art Unit

1632

SEARCHED

Class	Subclass	Date	Examiner
800	13		
800	18		
800	21		
536	23.5		
536	24.1		
435	455	8/14/2006	<i>gm</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
800	18		
800	13		
800	21		
526/23.5, 24.1, 435/455, AU interference search		8/14/2006	<i>gm</i>

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated, inventor search, parents updated and reviewed.	8/14/2006	<i>gm</i>